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Assignee: 0-IN DESIGN AUTOMATION

Title: A METHOD FOR AUTOMATICALLY SEARCHING FOR
                 FUNCTIONAL DEFECTS IN A DESCRIPTION OF A CIRCUIT

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San Jose, California
May 4, 2001

BOX PATENT APPLICATION
COMMISSIONER FOR PATENTS
Washington, D. C. 20231

PRELIMINARY AMENDMENT

Dear Sir:

Prior to examination, please amend the above-referenced application as follows:

IN THE SPECIFICATION

Please replace the paragraph beginning at page 1, line 18, with the following

paragraph:

This application is a continuation of U.S. Patent Application Serial No. 08/954,765,

filed October 20, 1997. In addition, this application is related to and incorporates by

reference herein in its entirety the concurrently filed, commonly owned U.S. Patent

Application, Serial Number 08/955,329 [Attorney Docket Number M-5302 US] filed by

Tai An Ly, et al., and entitled "A Method for Automatically Generating Checkers for Finding Functional Defects in a Description of a Circuit".

In accordance with 37 CFR § 1.121(b)(1)(iii), Appendix A contains a marked up version of the amended paragraph illustrating the newly introduced changes in the specification.

IN THE CLAIMS

Please cancel claims 1-10. Please add new Claims 11 to 13, as follows:

11.   A computer-implemented method for determining defects in the functional behavior of a circuit, the functional behavior of the circuit including a plurality of states and a plurality of transitions between the states, the states including a current state, a plurality of next states reachable from the current state, and a reset state, the method comprising:

simulating the functional behavior of the circuit using a description of the circuit, wherein the simulating includes:

transitioning the simulation from the current state to a first next state;

transitioning the simulation from the current state to a second next state;

wherein transitioning from the current state to the second next state is performed automatically after transitioning from the current state to the first next state without entering the reset state; and

determining defects in the functional behavior of the circuit using the simulating.

12.   The method of Claim 11, wherein the simulation is set to the current state after transitioning to the first next state.

13.   The method of Claim 11, wherein the first transitioning is performed in response to a first test vector, and the second state transition is performed in response to a second test vector.

REMARKS

Please enter the above amendments prior to examination on the merits. If there are any question, please contact the undersigned at 408/453-9200.

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Respectfully submitted,

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Appendix A

The following is a marked up version of the amended paragraph beginning at page 1, line 18.

<u>This application is a continuation of U.S. Patent Application Serial No. 08/954,765, filed October 20, 1997. In addition, this</u> [This] application is related to and incorporates by reference herein in its entirety the concurrently filed, commonly owned U.S. Patent Application, Serial Number _____ [Attorney Docket Number M-5302 US] filed by Tai An Ly, et al., and entitled "A Method for Automatically Generating Checkers for Finding Functional Defects in a Description of a Circuit".